Search Notes					

Application/Control No.	Applicant(s)/Patent under Reexamination
10/708,849	SHIH ET AL.
Examiner	Art Unit
Thien F. Tran	2811

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Class	Subclass	Date	Examiner		
257	13,59 72,79 82-84 88	10/13/2005	т		
345	76,82	10/30/2005	Π		
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SEARCH NOT (INCLUDING SEARCH		
	DATE	EXMR
EAST	10/13/2005	TT
EAST	10/30/2005	TT
Interference Search History Printout	10/30/2005	π
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